Search Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/016,096	WEI ET AL.
Examiner	Art Unit
Christopher L. Lavin	2621

	SEARCHED			
Class	Subclass	Date	Examiner	
i				
		•		
_				
		,		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	,		
	reference Printout		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Updated East Search	11/1/2005	CLL
Interference Search History Printout	11/1/2005	CLL
*		
·	-	ļ.